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In re the application of
Lee D. Whetsel

TI-31205

SEP 01 2004

Serial No.: 09/845,879

Art Unit: 2133

Technology Center 2100

Filed: 4/30/2001

Examiner: P. Chung

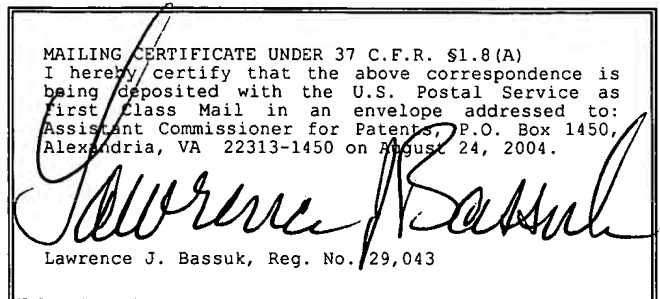
Title: Dual Mode Test Access Port Method and Apparatus

Amendment A Under 37 CFR 1.111

August 24, 2004

Asst. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313

Dear Sir:



Responsive to the Examiner's Action of 02/27/2004, please
amend this application as follows:

In the Title:

Insert a new title as follows:

IC TAP/SCAN TEST PORT ACCESS WITH TAP LOCK CIRCUITRY